

Comparative Neutron & Proton Single Event Effect Testing and International Standards

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Presented at Neutron Users Club

NPL

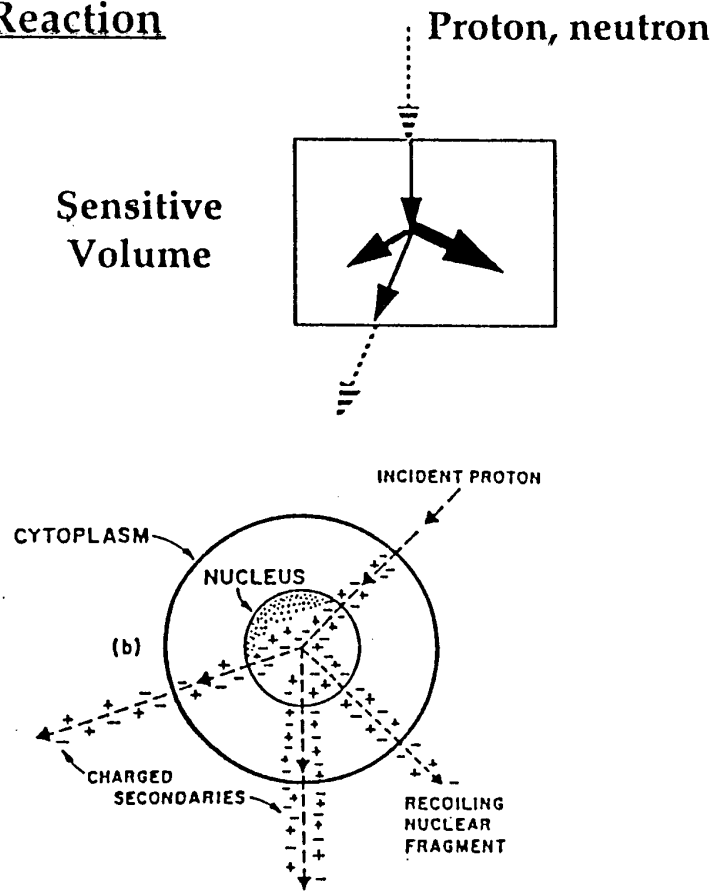
7 October 2004

SEE in COTS Microelectronics

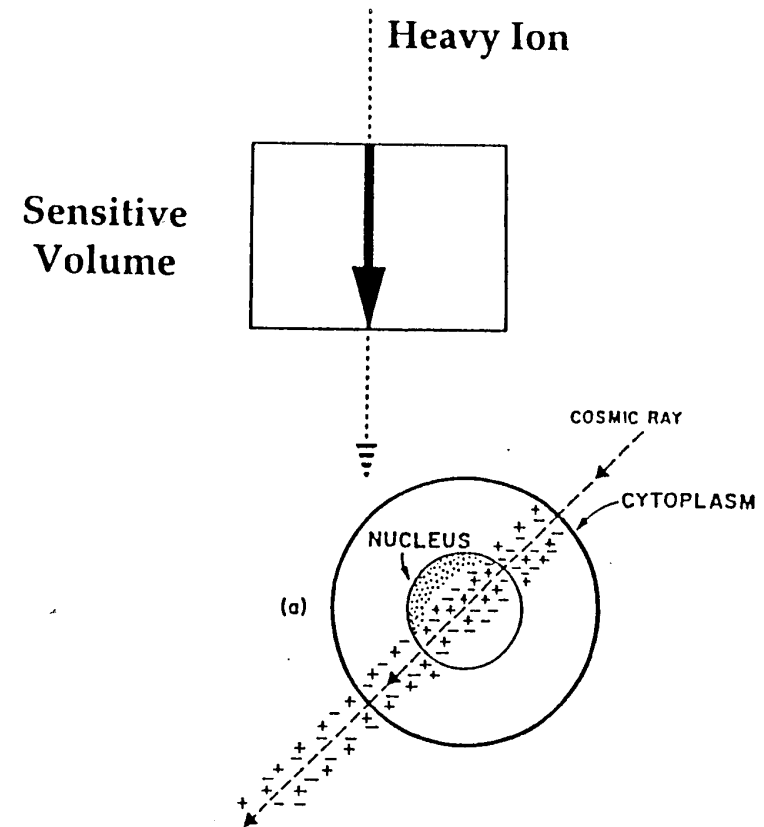
- **Single event effects** are induced by **single ionising particles**
 - Data corruption - single event or multiple-bit upsets
 - Device failure - eg Single Event Latchup (SEL), Gate Rupture (SEGR)
- SEEs are a growing problem for modern microelectronics:
 - Decreasing feature size and lower voltages - smaller critical charges
 - Higher frequency operation - previously transients from particle ionisation were too fast to be latched
 - Miniaturisation means more transistors affected by single ion - increased number of multiple bit upsets
 - Thinner gates - increased risk of gate rupture
- Growing evidence of such effects in aircraft and ground-based equipment as well as from spaceflight

SINGLE EVENT EFFECTS & RADIOBIOLOGICAL EFFECTS

Nuclear Reaction



Direct Ionization



SEE in COTS Microelectronics

- PERFORM computer withdrawn for tests in 1991 following accumulation of errors in SRAM memory.
- More than one upset per flight in 280 64K SRAMs on Boeing E-3 AWACS and NASA ER-2.
- Boeing-777 autopilot design altered after faults shown to correlate with altitude and latitude.
- Sun Enterprise Server crashes from upsets in L2 cache
- PCs on Shuttle and MIR required frequent reboot, typically every nine hours.

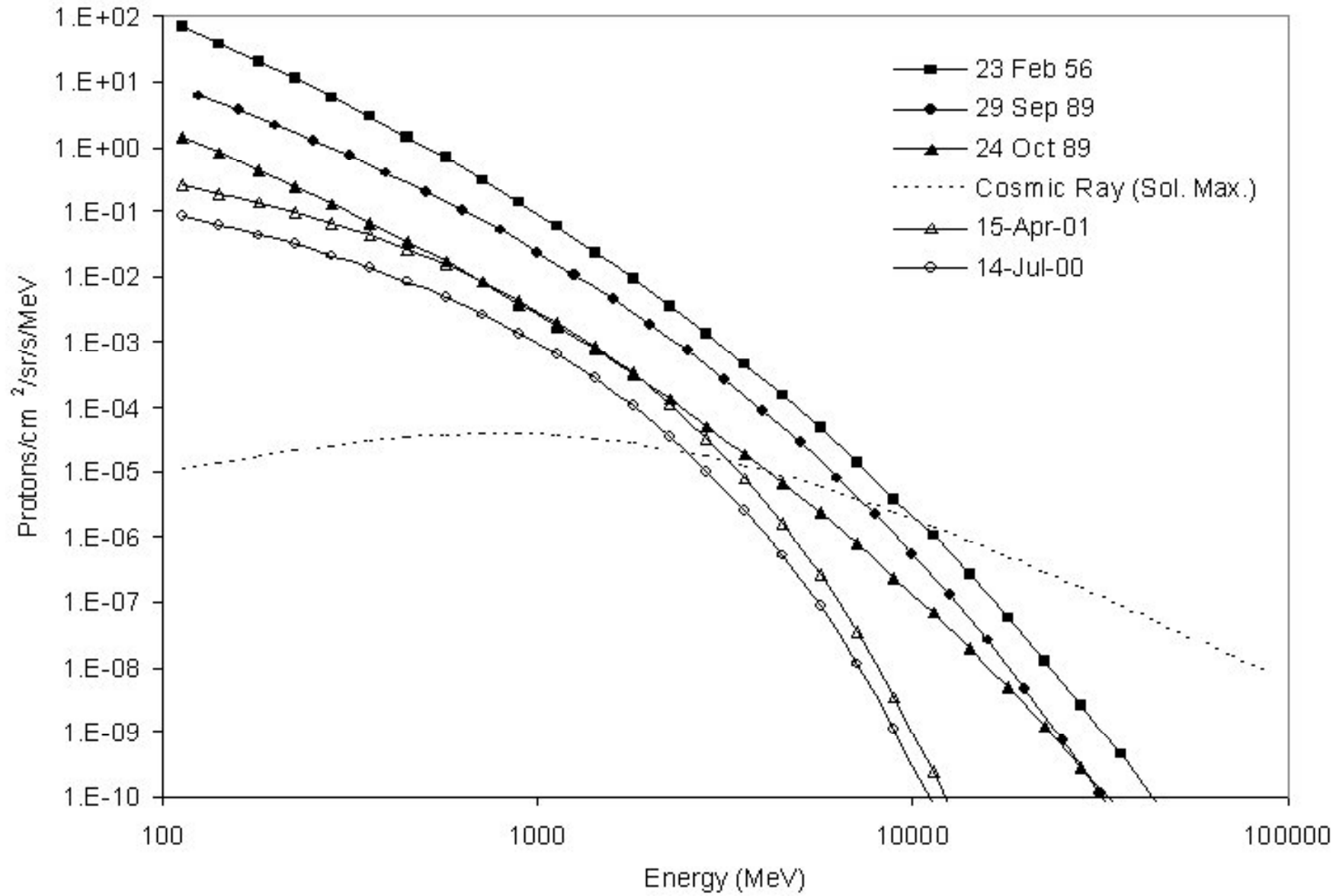
SEE in COTS Microelectronics

- Activities
 - Develop and validate atmospheric SEE threat models
 - Test microelectronics and compare with model results to better understand process which drive SEE susceptibility and trends with device technology
 - Modelling of nuclear interactions, energy deposition and charge collection in devices
 - Develop, with industry, standards for environment, test methodologies, and guidelines
- Complementary programmes funded by MOD (QinetiQ) and DTI (MBDA, BAE SYSTEMS, Goodrich, Smiths, Universities of Lancaster, Central Lancashire, Surrey).

WP1 Environments

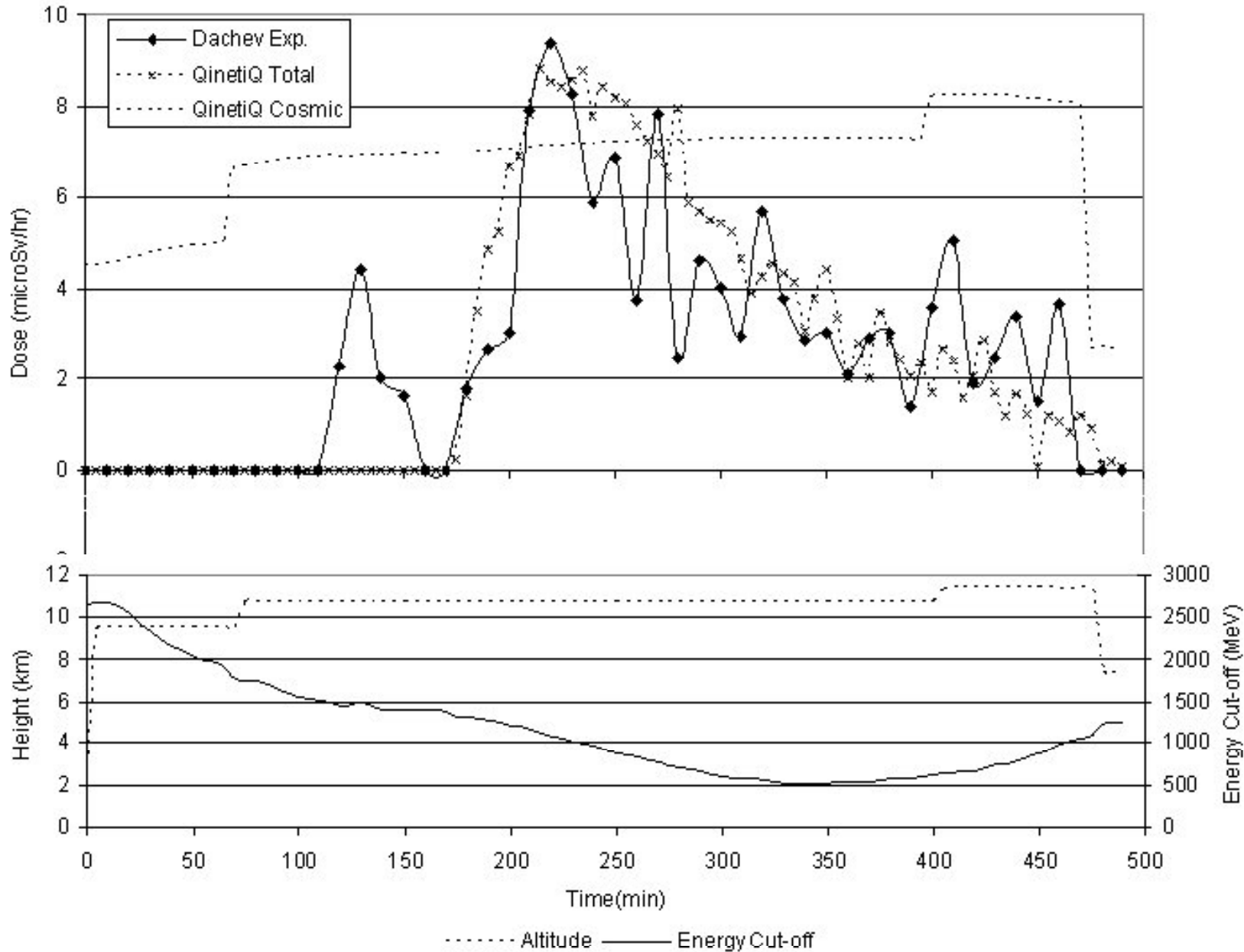
- Monte Carlo codes have been used to generate a database of atmospheric secondary particle production as a function of incident cosmic ray energy
- Ground level neutron monitor data have been obtained for the major solar particle events of the current solar maximum.
- These have been combined with space data to generate the solar particle spectra and particle fluxes throughout the atmosphere.
- Flights of the CREAM monitor have been made to 49000 ft.
- A prototype compact monitor has been built and calibrated at The Svedberg Laboratory in Sweden.

Spectra of large solar particle events of cosmic rays

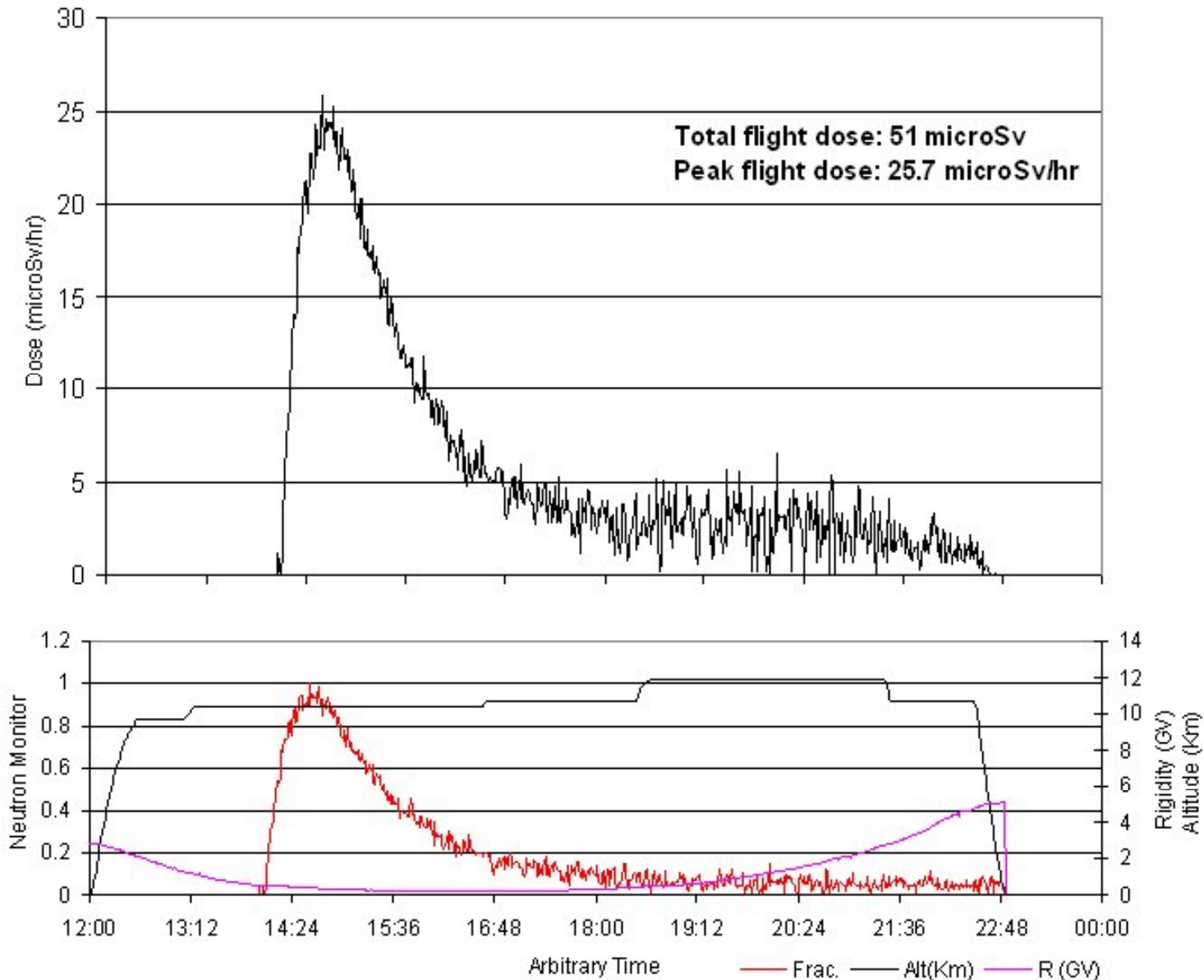


Comparison with experimental data

Prague – JFK
15th April 2001



Consequences of 15th April 2001 event for LHR-LAX flight



Upset Rates in 1 Gbyte of SRAM (Cross-Section of 5×10^{-14} cm² per bit)

Event	Neutron Flux /(cm ² -sec)	Upset Rate (/hr)	MTBU (sec)
1GV - 17km			
23-Feb-56	2893	1164	3.1
29-Sep-89	487	196	18.4
19-Oct-89	39.1	15.7	229
22-Oct-89	70.4	28.3	127
24-Oct-89	79.7	32.1	112
GCR (Sol. Max)	9.3	3.6	1003
1GV - 12km			
23-Feb-56	1113	493	7.3
29-Sep-89	191	84.7	42.5
19-Oct-89	16.1	7.1	504
22-Oct-89	28.2	12.5	288
24-Oct-89	31.5	13.9	258
GCR (Sol. Max)	5.8	2.5	1468

WP2 Ground Irradiations

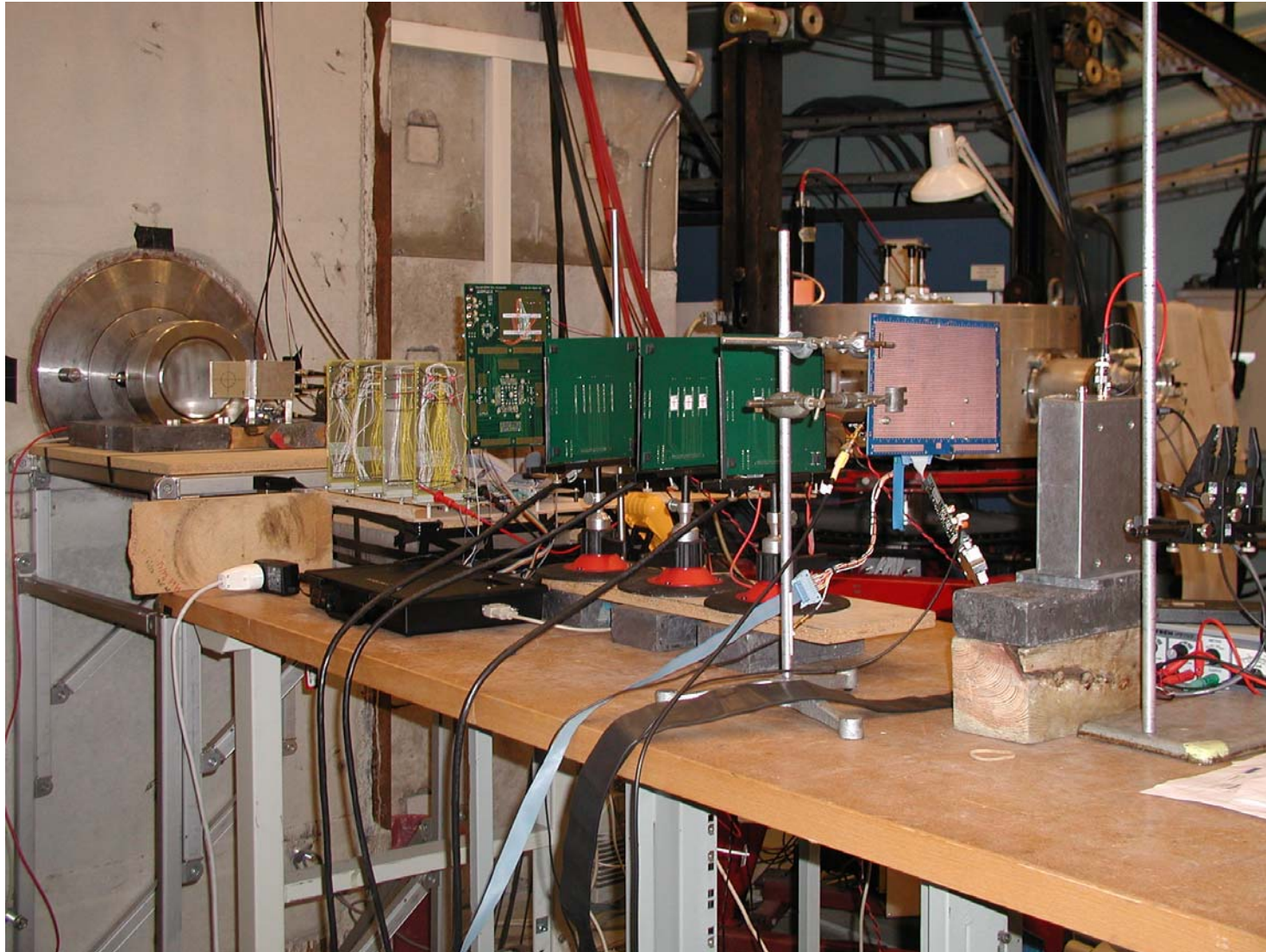
- Comparative results on SRAMs obtained using :
 - protons (13.5 to 490 MeV) at TRIUMF, Vancouver.
 - ions (xenon, argon) at UCL, Belgium.
 - neutrons (20-180 MeV) at TSL, Sweden
 - neutrons (14 MeV) from D-T at NPL, UK.
 - thermal neutrons at NPL, UK.
 - spallation neutrons at LANL, USA (Nov 2003).
 - pulsed laser via collaboration with MBDA Bristol.
 - flash X-ray at EROS. AWE (April 2003)
 - new devices tested at TSL in May 2004.

Old 4-MEGABIT SRAM PARTS now comprehensively tested

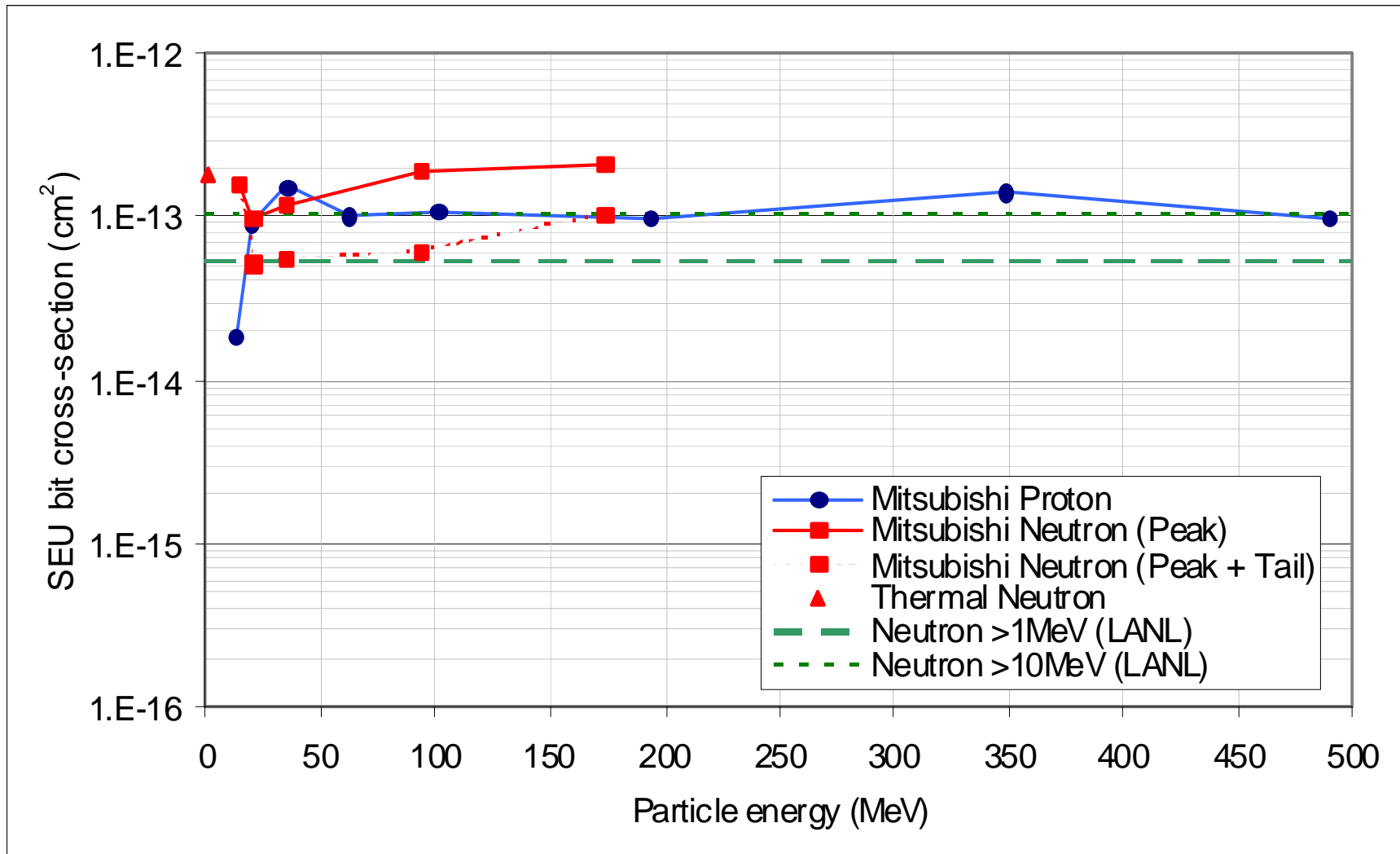
manufacturer	reference	date code	minimum feature size (μm)
Hitachi	HM628512ALP-7	9809	0.5
Hitachi	HM628512BLP-7	9925	0.35
Toshiba	TC554001FL-70L	9827	0.5
Toshiba	TC554001AF-70L	9929	0.4
Mitsubishi	M5M5408AFP-70LL	9839	0.4
Samsung	KM684000BLP-7L	9844	0.4

Testing at The Svedberg Laboratory

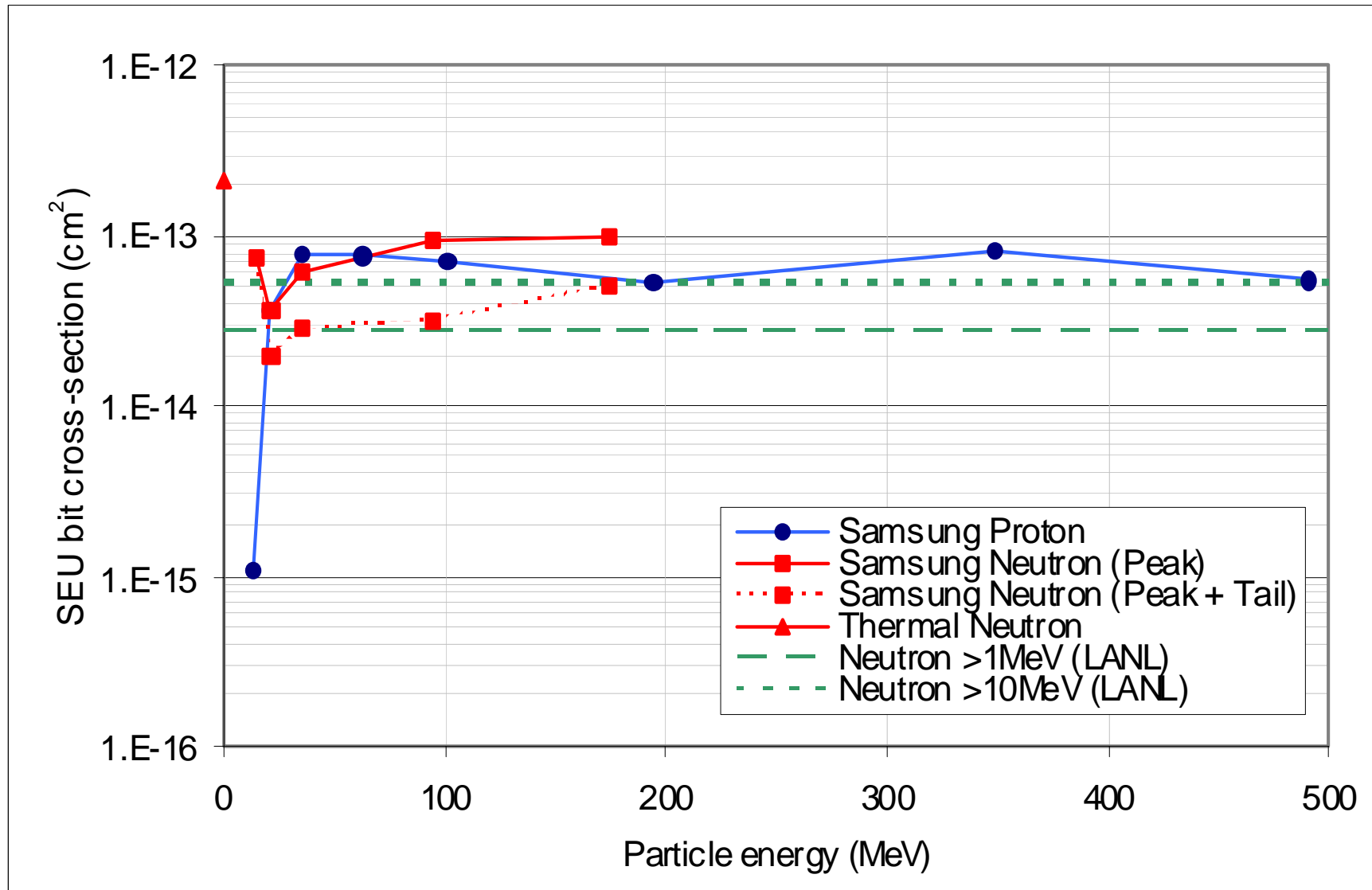
May 2004



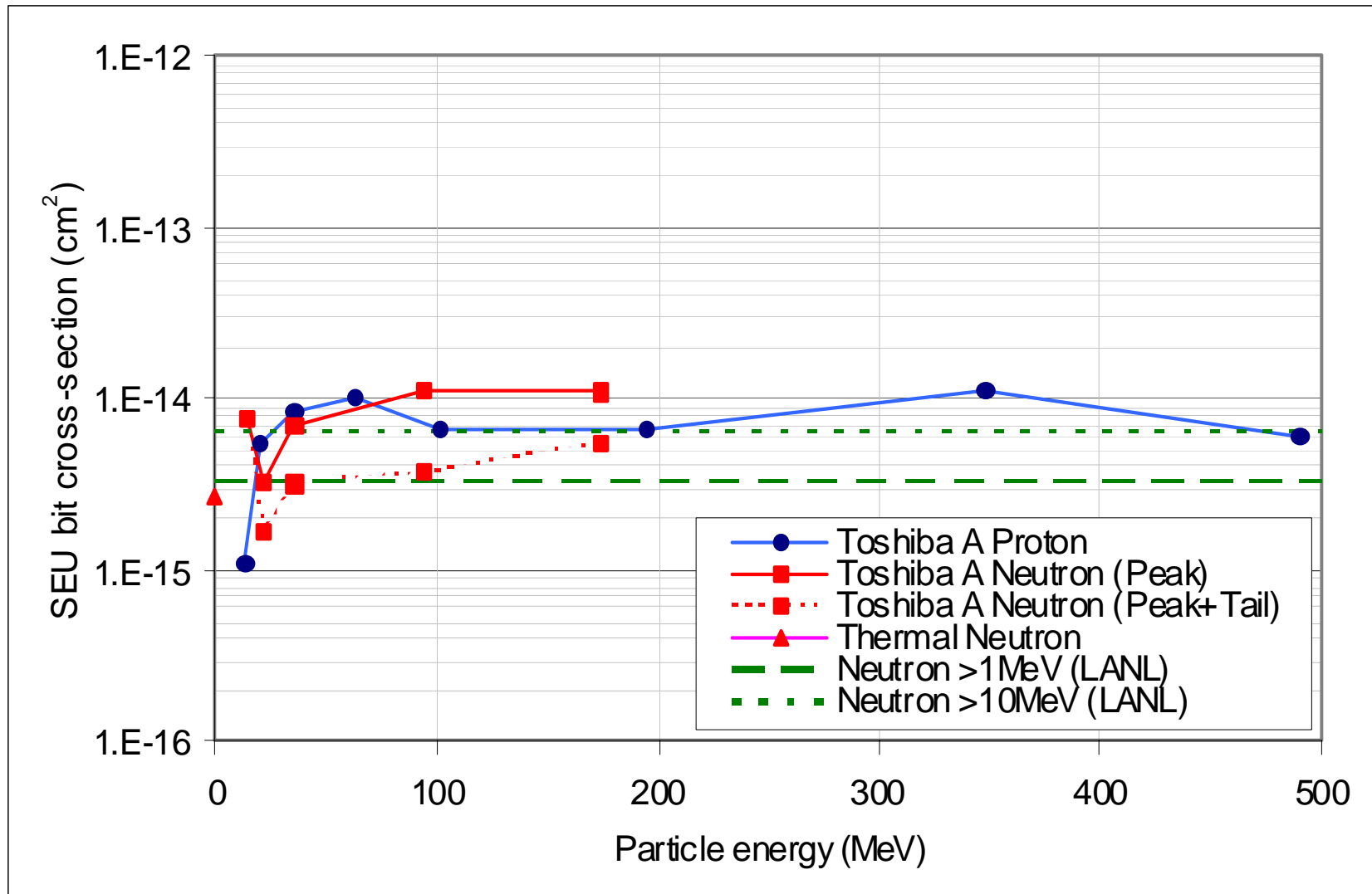
Proton and Neutron Experimental Data for the Mitsubishi Device



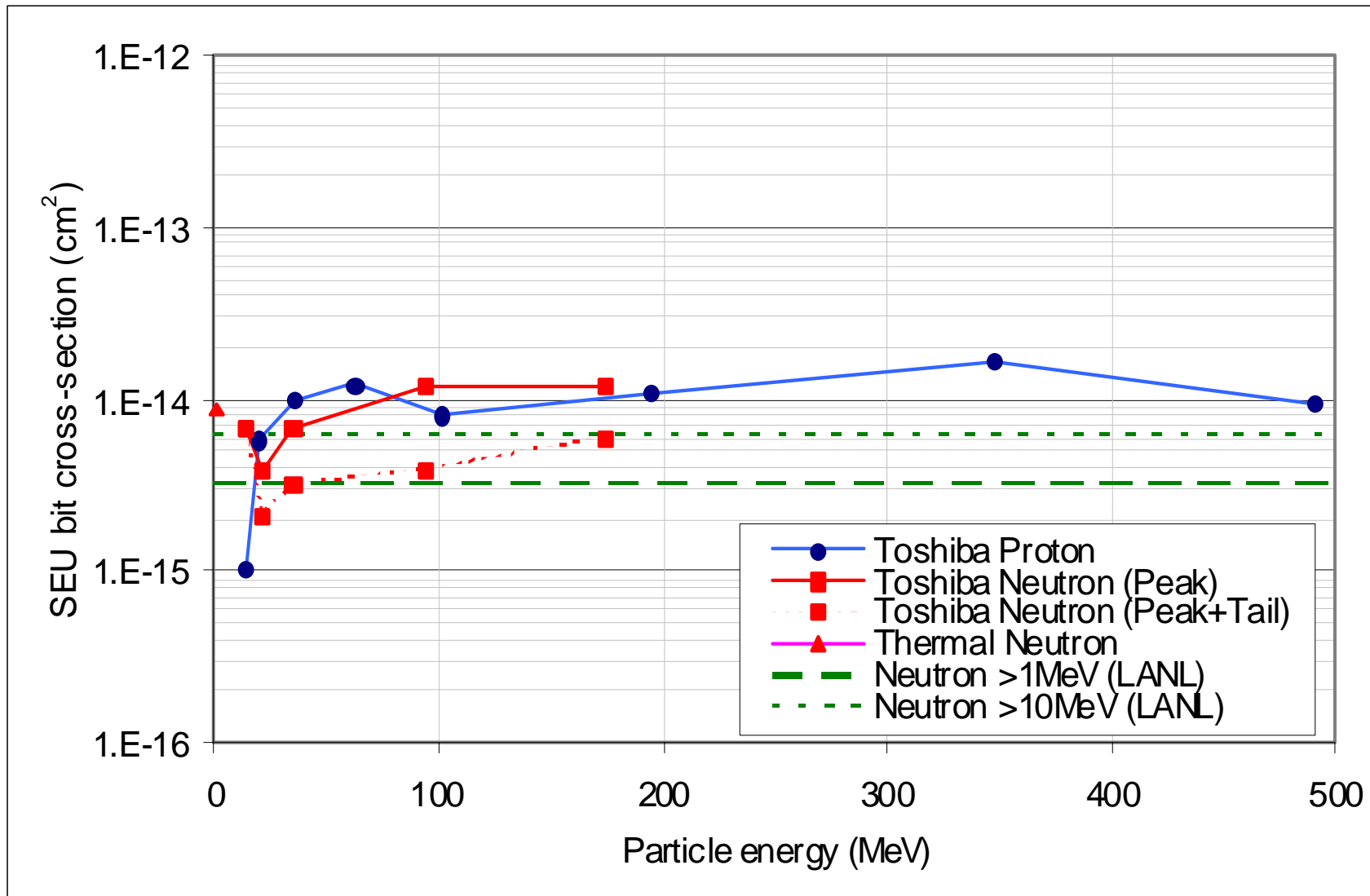
Proton and Neutron Experimental Data for the Samsung Device



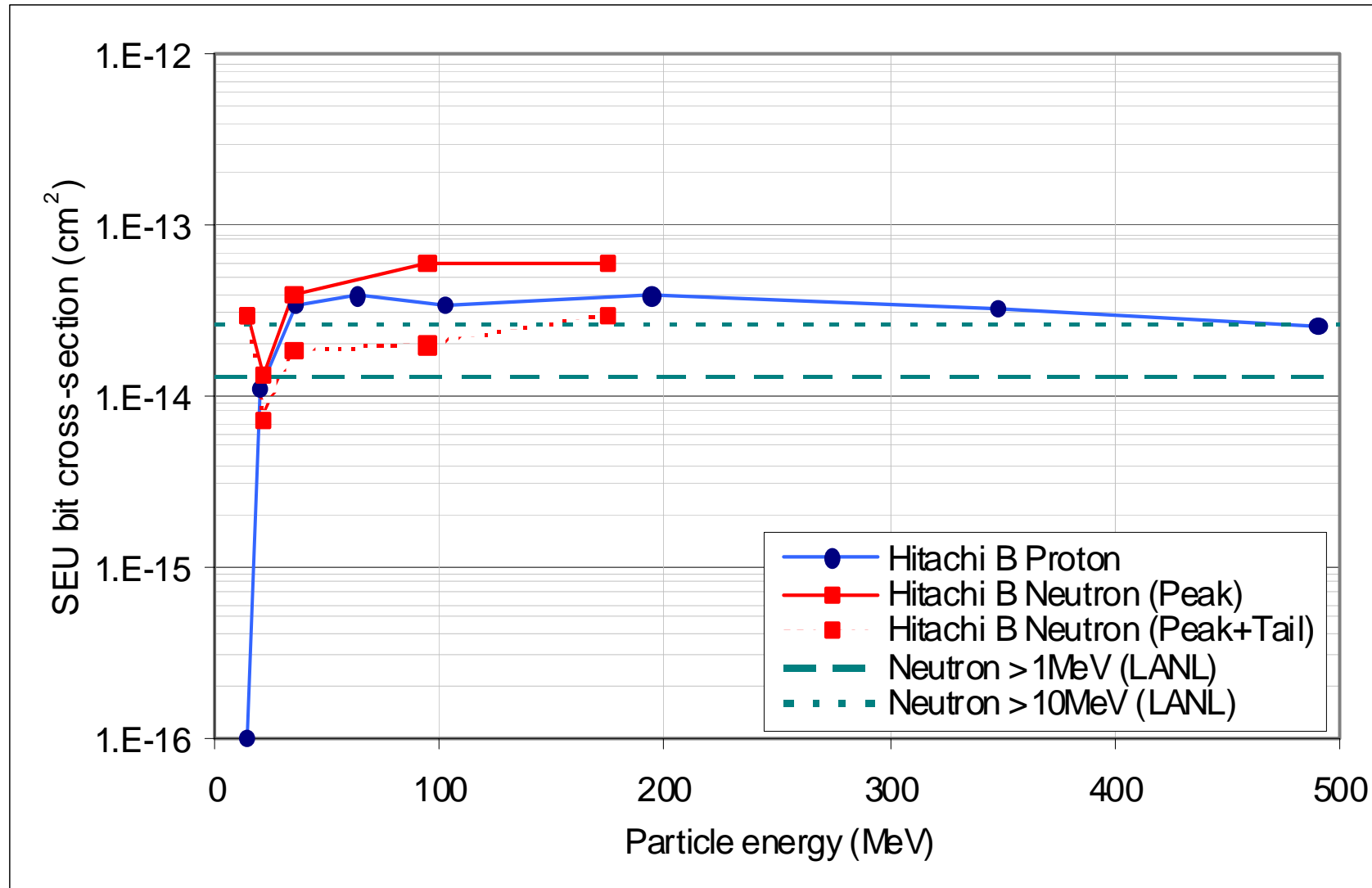
Proton and Neutron Experimental Data for the Toshiba A Device



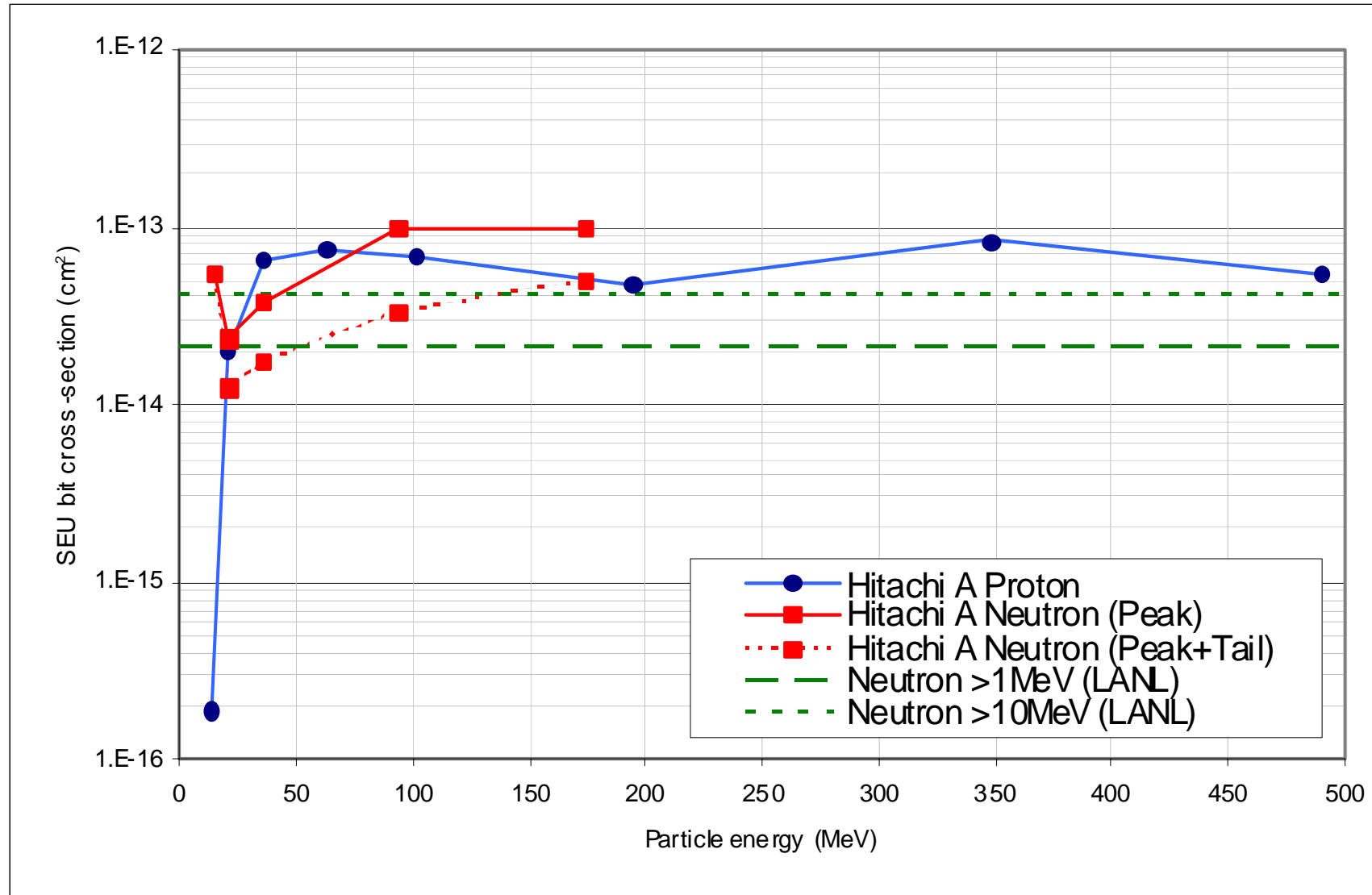
Proton and Neutron Experimental Data for the Toshiba Device



Proton and Neutron Experimental Data for the Hitachi B Device

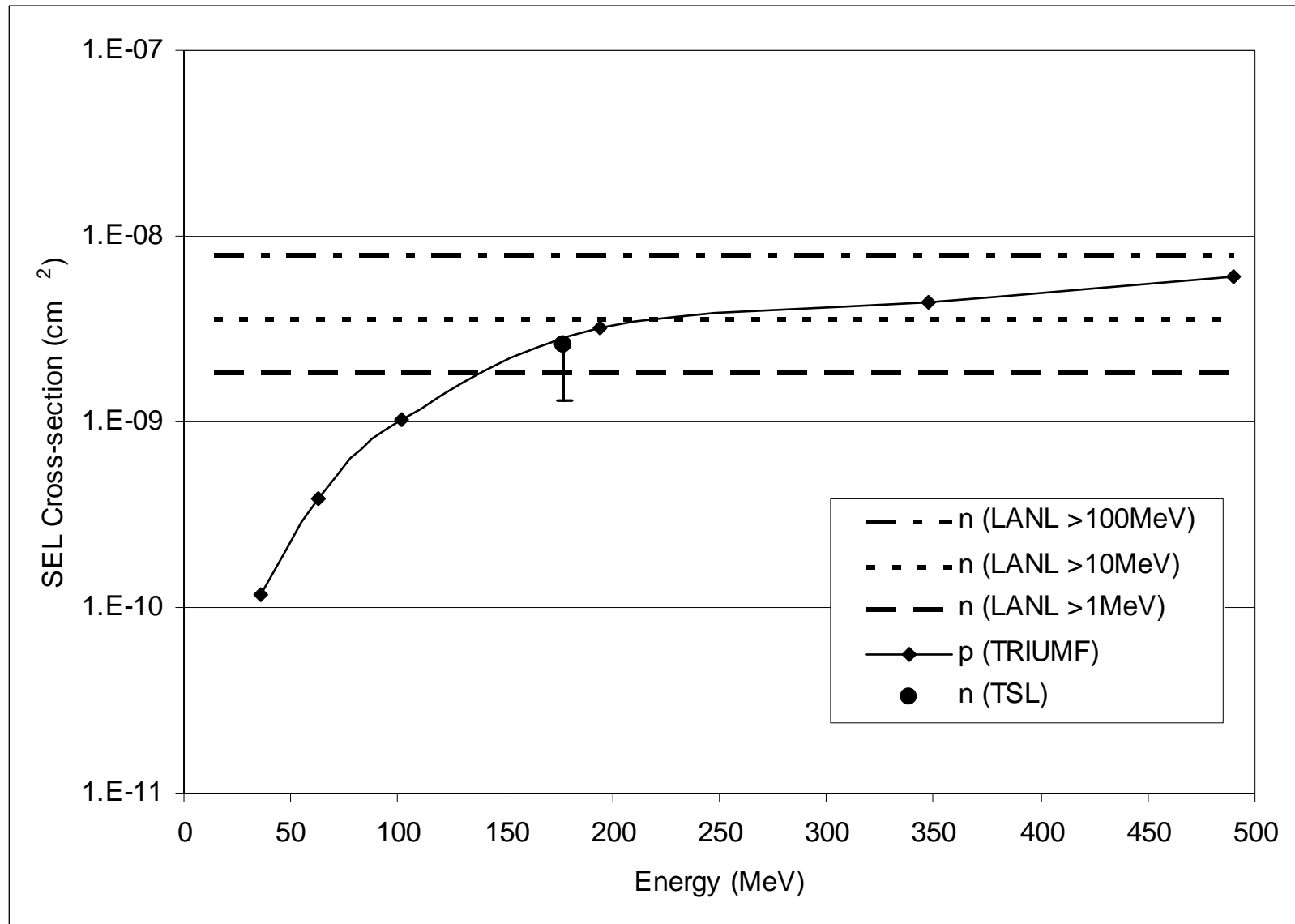


Proton and Neutron Experimental Data for the Hitachi A Device

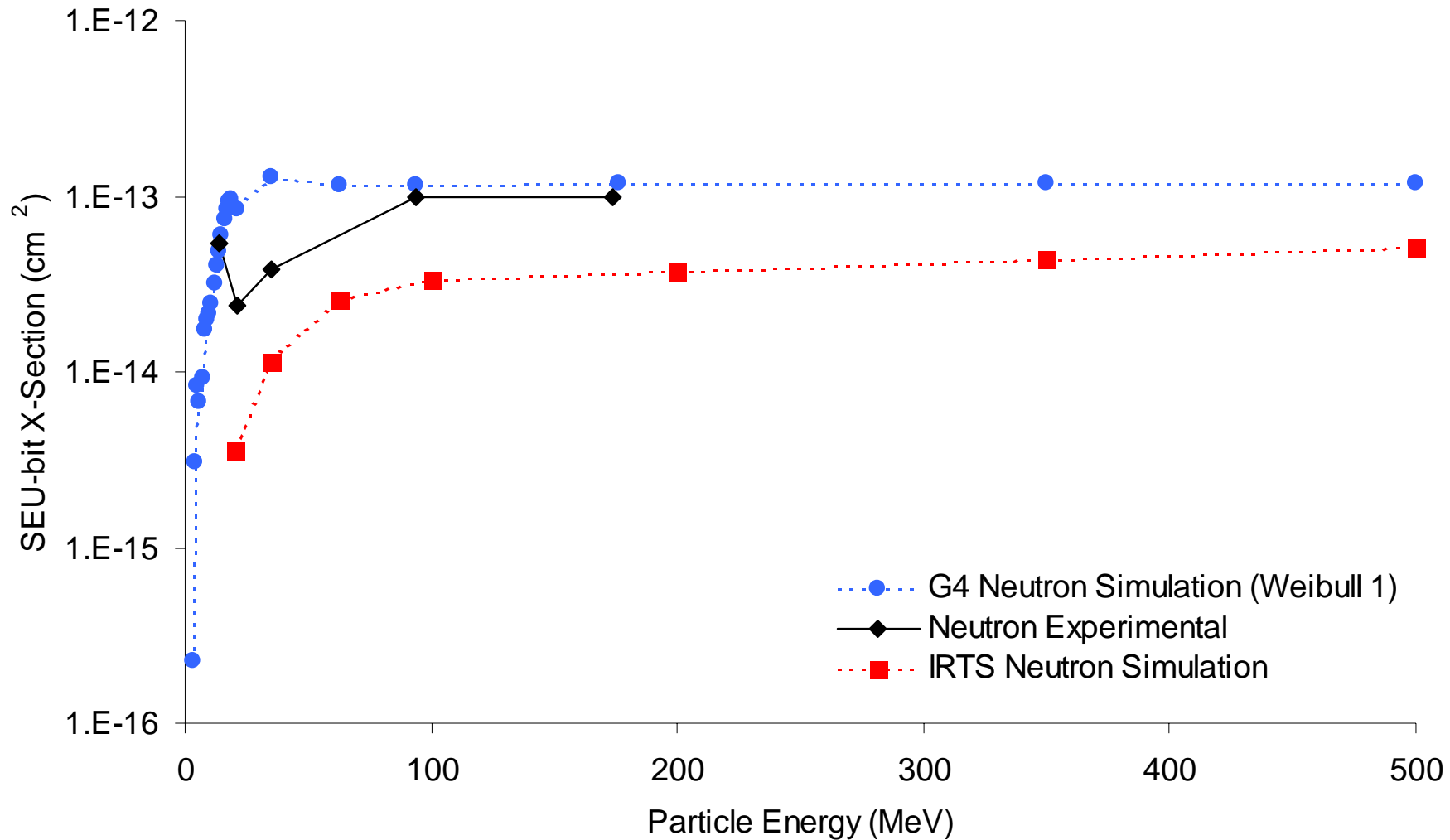


Device	Thermal neutron bit cross-section (cm ²)	Fast neutron bit cross-section (cm ²)	Thermal-fast ratio
Hitachi A	0	7.06×10^{-14}	-
Hitachi B	0	4.24×10^{-14}	-
Toshiba	8.7×10^{-15}	8.35×10^{-15}	1.04
Toshiba A	2.7×10^{-15}	7.75×10^{-15}	0.35
Samsung	2.1×10^{-13}	7×10^{-14}	3
Mitsubishi	1.8×10^{-13}	1.41×10^{-13}	1.28

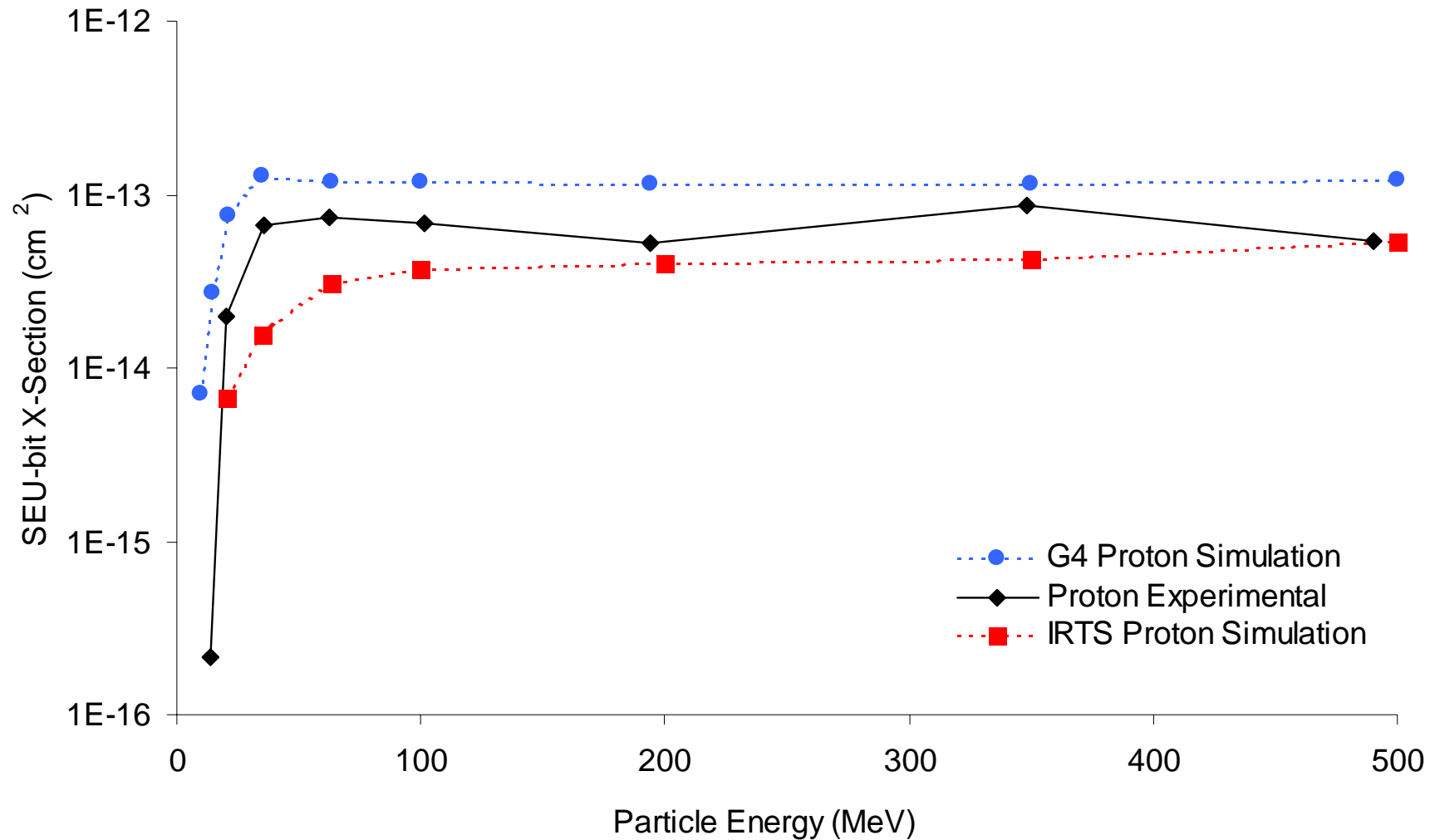
Proton & neutron latchup cross-sections for Hitachi-B 4Mbit SRAM



Neutron Cross-Sections for Hitachi-A 4-Mbit SRAM: Experimental and Simulation Comparison



Proton Cross-Sections for Hitachi-A 4Mbit SRAM: Experimental and Simulation Comparison



WP4 SEE Predictions and Guidelines

- International Electrotechnical Commission TC107
“Standard for the Accomodation of Atmospheric Radiation Effects [SEE] within Avionics Electronic Equipment.”
 - Scope is avionics up to 60000 feet.
 - Main participants are Goodrich, Boeing, Honeywell, Airbus, Smiths, QinetiQ.
 - About to be issued as Committee Draft.
 - Paper at NSREC04 Workshop, July 2004.
- Work recently started on revision of JESD89 “Measurement and Reporting of Alpha-Particles and Terrestrial Cosmic-Ray Induced Soft Errors in Semiconductor Devices”
 - Sea level to 10000 feet.

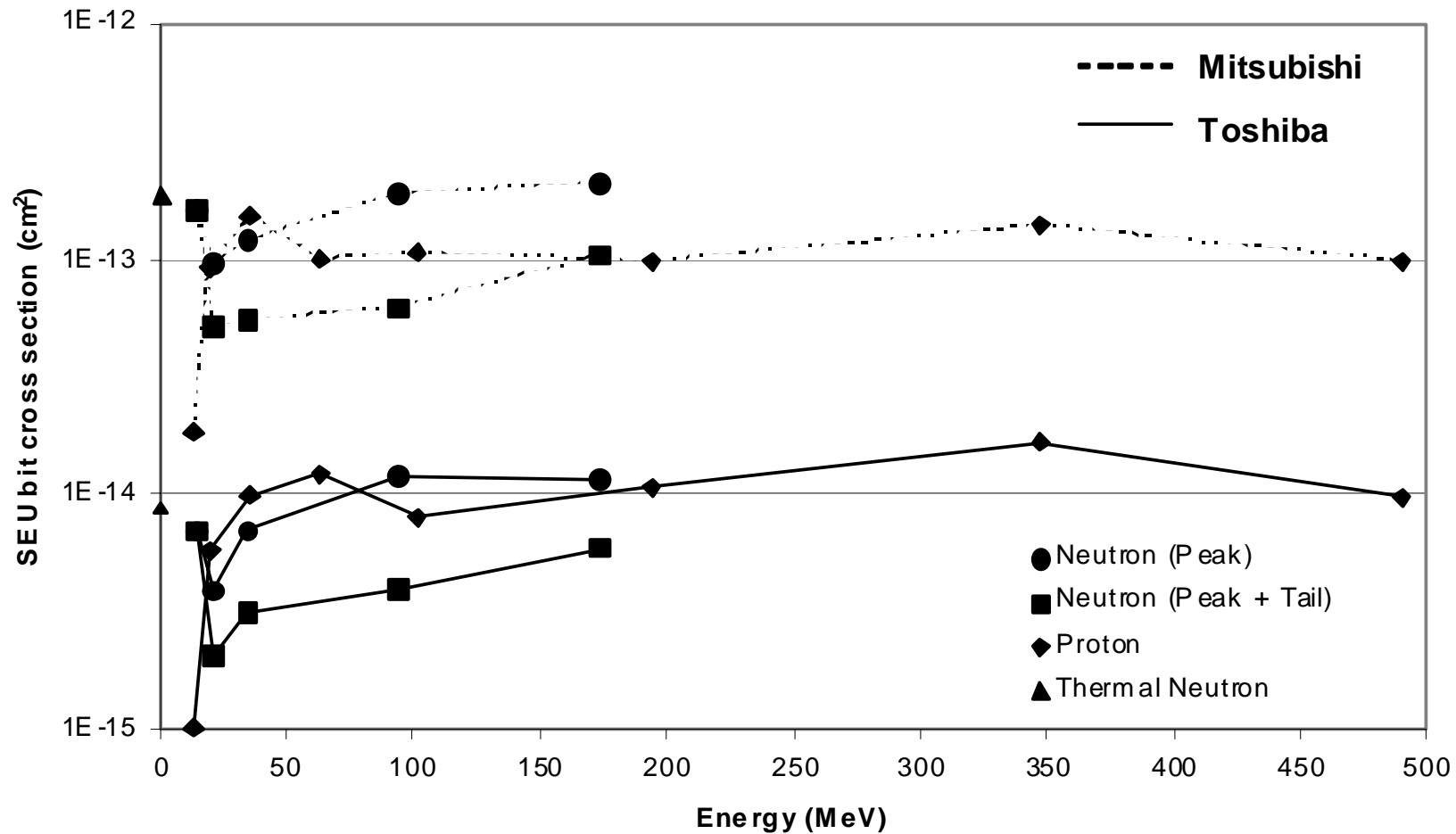
IEC TC107 on Atmospheric Radiation Effects

- Contents:
 - Scope
 - Normative References
 - Terms and Definitions
 - Introduction
 - Radiation Environment of the Atmosphere
 - Effects of Atmospheric Radiation on Avionics
 - Guidance for System Designs
 - Determination of Avionics SEE Rates
 - Considerations for SEE compliance

IEC TC107 on Atmospheric Radiation Effects (continued)

- Annexes:
 - Thermal Neutron Assessment
 - Methods of Calculating SEE Rates in Avionics
 - Review of Test Facility Availability
 - Tabular Description of Variation of Atmospheric Neutron Flux with Altitude and Latitude.
 - Bibliography
 - Technical References

Data from this work essential to comparing test methods



Test Facility Needs

- Spallation neutron source
 - Los Alamos becoming difficult
 - TRIUMF limited test rate
 - CERF low intensity, ? availability
- Monoenergetic neutron sources; eg TSL
 - problems of low energy tail, intensity
- Low energy sources: D-T, D-D, fission, Am-Be, thermal
 - Problems of intensity, availability
- Protons are reasonable proxy at high energies but not at low (< 20 MeV).